

[S.] 05-SPUB-USPAT1-0-000 ELEMENT UNCLASSIFIED  
 Default group: 00

**L9 same L8**

5.002/142ko

- ☒ Drafts
  - ☒ BRS:
  - ☒ BRS:
  - ☒ BRS:
  - ☒ BRS: knall
  - ☒ BRS: 19 21 23
  - ☒ BRS: 32with 33
- ☒ Pending
- ☒ Active
  - ☒ L1: (515589) drain
  - ☒ L2: (1360957) test
  - ☒ L3: (2035133) ( trench\$2 recess\$4) groove
  - ☒ L4: (1060780) select
  - ☒ L5: (728094) transistor tft
  - ☒ L6: (1897154) vertical
  - ☒ L7: (20720) L5 near2 (L6 L4 L3)
  - ☒ L8: (244) L7 same L2
  - ☒ L9: (3548) L2 near12 L1
  - ☒ L10: (7) L9 same L8
- ☒ Failed
- ☒ Saved
  - ☒ S2: (1) 09/948877

	U	I	Inventor	Document	Issue P	Title	Current	Current X	Retrieval S	C	P	Z	S	A	R	Image Doc P	
1			Wang, Jianguo et al.	US 20040208 065 A1	2004 3 1021 0	Methods and circuits for testing programmability of a semiconductor memory cell and memory array using	365/18 2									US 20040208 065	
2			Pio; Federico et al.	US 6128219 A	2000 2 1003 3	Nonvolatile memory test structure and nonvolatile memory reliability test method	365/18 5.09	365/185.0 5;								US 6128219	
3			Kowalski, Bernhard et al.	US 20050040 308 A1	2005 1 0224 2	Test structure for improved vertical memory arrays	257/48									US 20050040 308	
4			Kamoshida Masahiro	US 20050002	2005 2 0108 3	Shared sense amplifier scheme semiconductor memory device and	365/20 1									US 20050002	